



Substituted forms PTO/SB/08a & PTO/SB/08b  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>		Application Number	10/701,833
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		First Named Inventor	Elmer G. Fridrich
		Art Unit	1753 1742
		Examiner Name	
Sheet 1 OF 1		Practitioner Docket No.	EF-101 F

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/Nicholas Smith/  
Examiner Signature

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Date Considered